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H3H
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(54) Analogue to digital converters

(57) An analogue to digital converter comprises a plurality of amplifiers (32) whose inputs are fed with an analogue signal via a resistor chain (R1 to Rn). The amplifier outputs are coupled to a decoding logic and output latch circuit (31) which generates a digital output corresponding to the analogue input. The arrangement reduces the effects of sampling-skew and can thus operate at high frequencies.

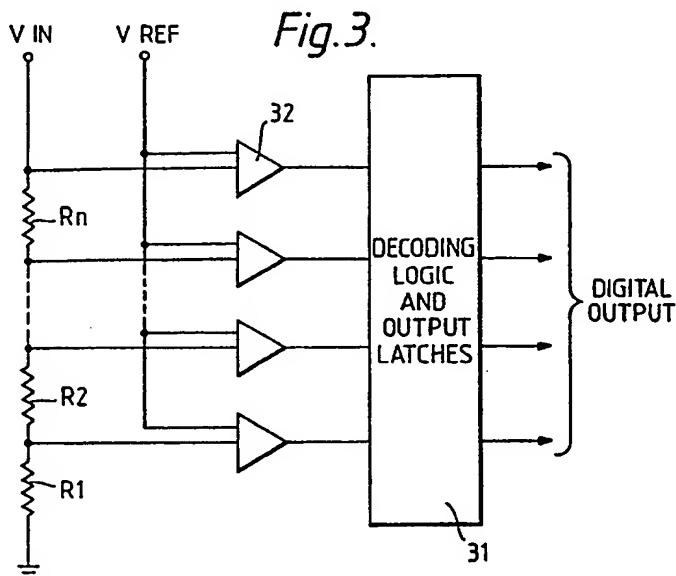
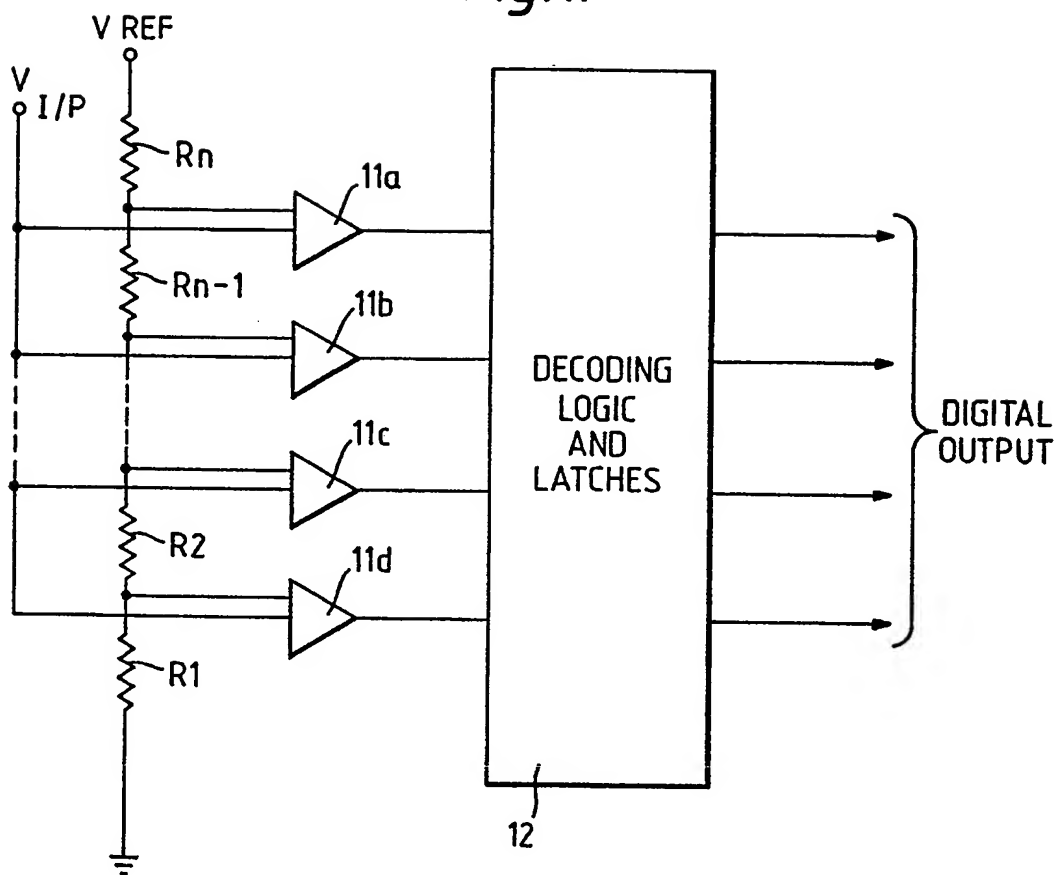
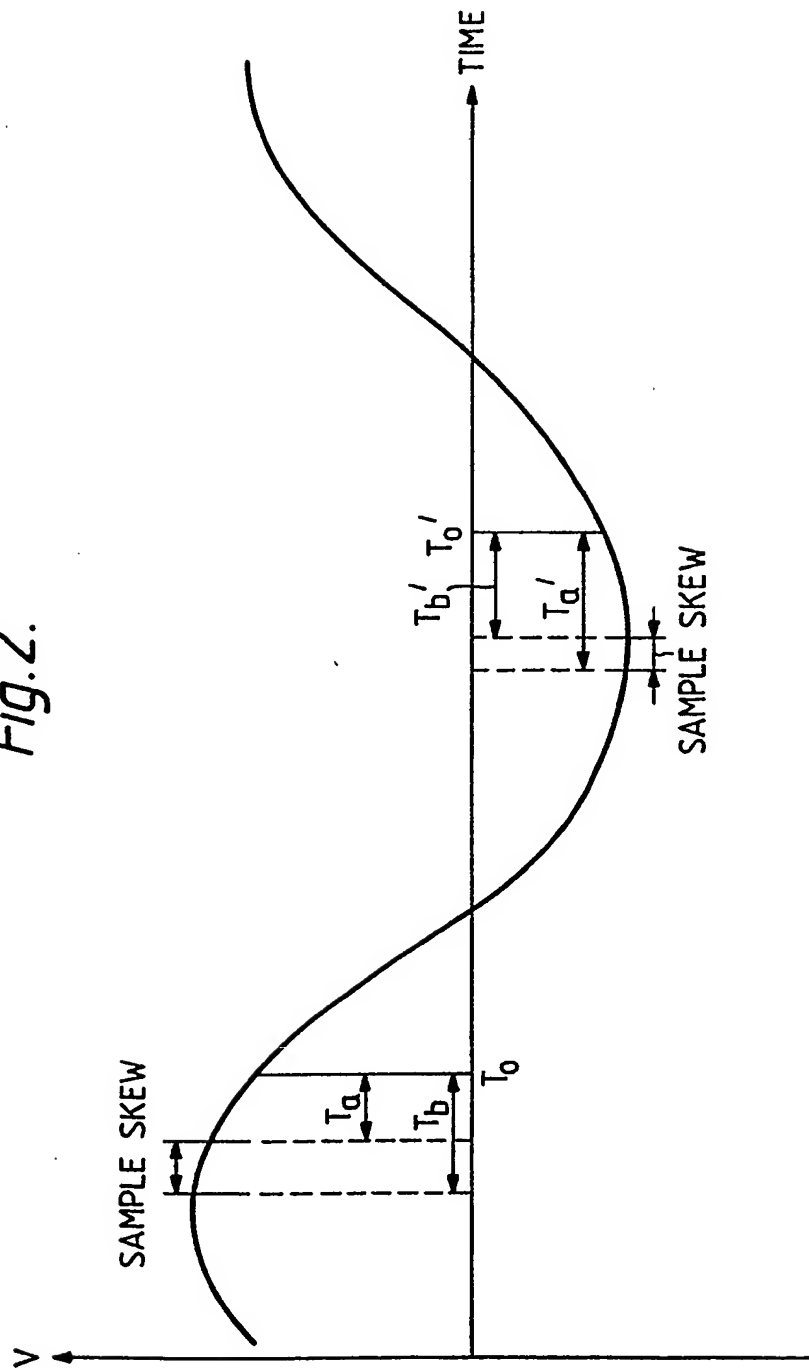


Fig. 1.



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Fig. 2.



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Fig.3.

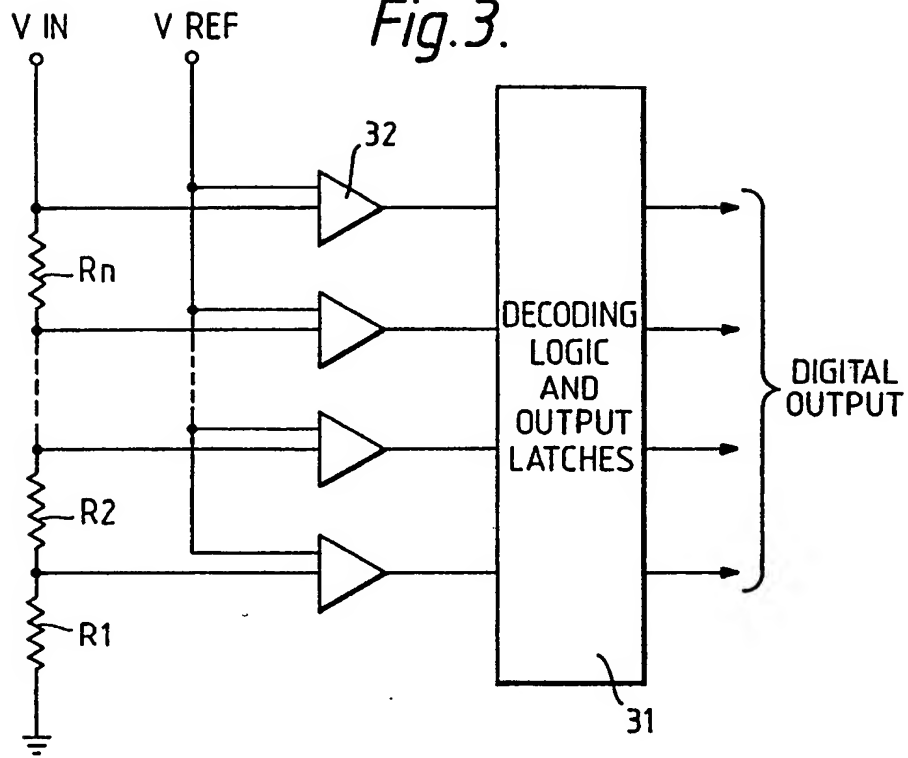
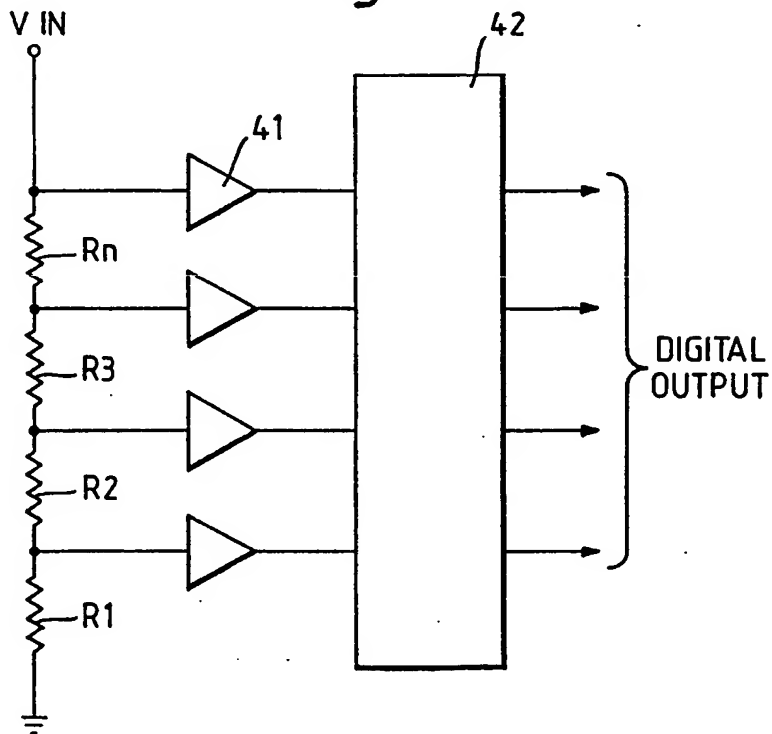


Fig.4.



SPECIFICATION

Analogue to digital converters

5 This invention relates to analogue to digital converters and in particular to an architecture for high speed
converters. Conventional high-speed ('flash') analogue-to-digital converters (ADCs) are generally organised
with the architecture illustrated in Figure 1 of the accompanying drawings. In this construction a parallel row
of comparators (11) is fed with the input (analogue) signal V_{in} , and each comparator compares this input with
a reference signal derived from a reference voltage V_{ref} via a resistor chain R1 to Rn. Each comparator 11
10 which has a reference signal less than the input signal at the sampling time will have an output in one state
(either 'high' or 'low'), while the other comparators with a reference signal greater than the input signal will
have an output in the opposite state. The output of the row of comparators is thus comparable to a
thermometer scale, with the magnitude of the input signal at the sampling time indicated by the position of
the change in comparator output from one state to another. A decoding logic and output latch circuit 12 can
15 then convert this thermometer scale output into any required digital format (e.g. magnitude-only or two's
complement).

Limitations to the speed at which this architecture can operate come from two main areas. Firstly, the
speed at which the latches can be clocked is limited, and secondly the propagation delay from the input
through to the outputs may vary, depending upon which path is followed, and this will cause errors in the
20 digital output if the input signal bandwidth is too high. Figure 2 of the accompanying drawings illustrates the
operation of the circuit of Figure 1. Referring to Figure 2, a clock edge triggering the output latches at time T_0
is effectively sampling the state of the input signal V, e.g. of comparator 11a, some time T_a earlier, where T_a is
the propagation delay between the input and that output. This delay is not constant but will vary according to
the signal condition at the comparator input. Similarly a delay T_b is exhibited by comparator 11b and so on.
25 As the propagation delay varies with the signal path examined, then each output latch will be effectively
sampling the input signal at a different time, and thus at different states. Thus, at the next sampling time,
delays T_a and T_b different from T_a and T_b are experienced. To make matters worse the relative magnitudes of
the delay times may be reversed. This spread of sampling times or sampling-skew, sometimes referred to as
the 'aperture uncertainty', can be ignored if the spread in the values of the input signal being sampled is small
30 compared to the resolution of the ADC concerned. However, in practice this is difficult to insure, and limits
the maximum frequency of the input signal can be sampled.

The object of the present invention is to minimise or to overcome this disadvantage.

According to the invention there is provided an analogue to digital converter, including a plurality of input
amplifiers, a resistor chain each node of which is coupled to an amplifier input and via which, in use, an input
35 analogue signal is fed to the amplifier, and a decoding circuit coupled to the amplifier outputs whereby a
digital signal corresponding to the input analogue signal is generated.

One of the chief causes of sampling-skew in a conventional analogue to digital converter is the delay
variation in the comparators. Each comparator receives a different reference signal and is thus under
different bias conditions. Thus each comparator is subject to a different propagation delay. We have found
40 that this disadvantage of conventional converters may be overcome by providing a common reference signal
thus providing uniform bias conditions.

Embodiments of the invention will now be described with reference to Figures 3 and 4 of the
accompanying drawings, in which:-

Figure 3 is a schematic circuit diagram of a high speed analogue to digital converter; and

45 *Figure 4* shows an alternative converter construction.

Referring to Figure 3, the converter includes a decoding logic and output latch circuit 31 having a plurality
of inputs to each of which a two-input amplifier or comparator 32 is coupled.

One input of each comparator 32 is directly coupled to a reference voltage source V_{ref} . An analog input
signal V_{in} is fed to the other inputs of the comparators 32 via a resistor chain R1 to Rn, the comparator inputs
50 being connected one to each node of the chain. The comparator outputs are coupled to the decoding logic
and output latch circuit 31 which circuit generates a digital output corresponding to the analogue input. The
relative values of the resistors R11 to R14 are chosen such that a linear A/D converter is provided. Although
four comparators are chosen it will be appreciated that the technique is not so limited.

As the comparators 32 will receive the same reference signal there is no variation in propagation delay.

55 Slight aperture uncertainty will of course arise from the delay of the input signal as it passes along the
resistor chain which is loaded by the input capacitance of each comparator. This effect can be rendered
insignificant to using small value resistors. Further, a buffer input stage (not shown), e.g. a source or emitter
follower, may be provided at the input of each amplifier to reduce the input capacitance of the converter.

The values of the resistors R1 to Rn are preferably such that a linear conversion is provided. Each resistor
60 value may be calculated from the following formula:-

$$R_n = -V_R R_T \left[\frac{1}{V_m \left(\frac{N-n}{N} \right) - V_R} - \frac{1}{V_n \left(\frac{N-n+1}{N} \right) - V_R} \right] \quad 2 \leq n \leq N$$

and

$$R_1 = R_T - \sum_{i=2}^N R_i = -V_R R_T \left[\frac{1}{V_m \left(\frac{N-1}{N} \right) - V_R} \right]$$

wherein

- V_R is the reference voltage
 R_T is the total input impedance
 V_m is the maximum input voltage
 N is the number of quantization levels.

Thus, in a typical example where a 4 bit converter having 16 quantization levels and an input impedance of 50 ohms is required, the following resistor values have been calculated using the above formula. A reference voltage V_R of -1 volt and an input voltage in the range 0 to +1 volts were assumed.

$R_1 = 25.806 \text{ ohm}$	$R_5 = 1.085 \text{ ohm}$	$R_9 = 1.449 \text{ ohm}$	$R_{13} = 2.105 \text{ ohm}$
$R_2 = 0.860 \text{ ohm}$	$R_6 = 1.140 \text{ ohm}$	$R_{10} = 1.581 \text{ ohm}$	$R_{14} = 2.339 \text{ ohm}$
$R_3 = 0.920 \text{ ohm}$	$R_7 = 1.231 \text{ ohm}$	$R_{11} = 1.732 \text{ ohm}$	$R_{15} = 2.614 \text{ ohm}$
$R_4 = 0.985 \text{ ohm}$	$R_8 = 1.333 \text{ ohm}$	$R_{12} = 1.905 \text{ ohm}$	$R_{16} = 2.941 \text{ ohm}$

Further, a buffer input stage (not shown), e.g. a source or emitter follower, may be provided at the input of each amplifier to reduce the input capacitance of the converter.

An alternative construction is shown in Figure 4. As a common reference signal is employed it is not essential to use two-input comparators. Figure 4 shows a converter in which an input signal is fed via a resistor chain $R_1 - R_n$ to a plurality of single input amplifiers 41. Typically each amplifier 41 comprises standard logic inverter. The outputs of the amplifiers are fed to a decoding logic and output latch circuit 42 which provides a digital signal corresponding to the analogue input.

The analogue to digital converters described herein are intended for use in high capacity data transmission systems, but they are not of course so limited and can be employed in other, e.g. computer, applications.

CLAIMS

1. An analogue to digital converter, including a plurality of input amplifiers, a resistor chain each node of which is coupled to an amplifier input and via which, in use, an input analogue signal is fed to the amplifier, and a decoding circuit coupled to the amplifier outputs whereby a digital signal corresponding to the input analogue signal is generated.
2. An analogue to digital converter as claimed in claim 1, wherein the relative values of the resistors of said chain are such that a linear conversion is provided.
3. An analogue to digital converter as claimed in claim 1 or 2, wherein a buffer stage is provided at the input of each said amplifier whereby the input capacitance of that amplifier is reduced.
4. An analogue to digital converter as claimed in claim 1, 2 or 3, wherein said amplifiers are logic inverters.
5. An analogue to digital convertor as claimed in claim 1, 2 or 3, wherein said amplifiers are two-input comparators.
6. An analogue to digital converter substantially as described herein with reference to and as shown in Figure 3 or Figure 4 of the accompanying drawings.
7. A data transmission system incorporating analogue to digital converters as claimed in any one of claims 1 to 6.